ON Semiconductor®



Issue Date: 9 March 2017

Title of Change:	Change marking design and bonding method for WDFN6 devices					
Proposed first ship date:	ate: 20 June 2017 or earlier after customer approval					
Contact information:	Contact your local ON Semiconductor Sales Office or < Mutsuki.Niki@onsemi.com>					
Samples:	Contact your local ON Semiconductor Sales Office					
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <satoru.fujinuma@onsemi.com>.</satoru.fujinuma@onsemi.com>					
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <pcn.support@onsemi.com>.</pcn.support@onsemi.com>					
Change Part Identification:	Affected products will be identified with date code.					
Change category:	Wafer Fab Change 🛛 Assembly Change 🗋 Test Change 🔲 Other					
Change Sub-Category(s): Change Sub-Category(s): Manufacturing Site Change/						
Sites Affected:	plicable ON Semiconductor site(s) : External Foundry/Subcon site(s) ON Carmona, Philippines ON Shenzhen, China					

Description and Purpose:

This Process Change Notification is to notify customers of the following changes:

- Change marking design of WDFN6 to adopt the eject pin at mold release
- Change top mark from 3-liner to 2-liner
- Change WDFN device bonding method from bond stitch on lead to on ball (BSOB)

	Before Change Description				After Change Description					
Package design	No eject pin					Adopt the eject pin				
Part number	5111C01	5111C02	5111C05	5112C01	5132C01	5111C01	5111C02	5111C05	5112C01	5132C01
Marking design	05111 C01MT AYWW	05111 C02MT AYWW	05111 C05MT AYWW	05112 C01MT AYWW	05132 C01MT AYWW	C0501 AYWW	C0502 AYWW	C0505 AYWW	CB201 AYWW	CD201 AYWW •
bonding method		Die	Au wire			5	Bond stitch o	n Ball	FE	VCC GND T IC CS TST change point



Reliability Data Summary:

QV DEVICE NAME: LC05132C01NMTTTG PACKAGE: WDFN6

Test	Specification	Condition	Interval	Results		
TC	JESD22-A104	Ta= -55°C to +125°C	500 cyc	0/231		
PC	J-STD-020 JESD-A113	MSL 3 @ 260 °C	-	-		
Electrical Characteris	s are not impacted.					
	Part Number	Qualification Vehicle				
	LC05111C01MTTTG					
	LC05111C02MTTTG	LC05132C01NMTTTG				
	LC05111C05MTTTG					
	LC05112C01MTTTG					
	LC05132C01MTTTG					